

S/N 09/834,751

FEB 11 2005

PATENT

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

Applicant:	Sergey A. Velichko et al.	Examiner:	Craig Steven Miller
Serial No.:	09/834,751	Group Art Unit:	2857
Filed:	April 13, 2001	Docket:	303.750US1
Title:	CONCURRENT CONTROL OF SEMICONDUCTOR PARAMETRIC TESTING		

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**INFORMATION DISCLOSURE STATEMENT**

MS RCE  
Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

In compliance with the duty imposed by 37 C.F.R. § 1.56, and in accordance with 37 C.F.R. §§ 1.97 *et. seq.*, the enclosed materials are brought to the attention of the Examiner for consideration in connection with the above-identified patent application. Applicants respectfully request that this Information Disclosure Statement be entered and the documents listed on the attached Form 1449 be considered by the Examiner and made of record. Pursuant to the provisions of MPEP 609, Applicants request that a copy of the 1449 form, initialed as being considered by the Examiner, be returned to the Applicants with the next official communication.

Pursuant to 37 C.F.R. §1.97(b), it is believed that no fee or statement is required with the Information Disclosure Statement.

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Pursuant to 37 C.F.R. 1.98(a)(2), Applicant believes that copies of cited U.S. Patents and Published Applications are no longer required to be provided to the Office. Notification of this change was provided in the United States Patent and Trademark Office OG Notices dated October 12, 2004. Thus, Applicant has not included copies of any US Patents or Published Applications cited with this submission. Should the Office require copies to be provided, Applicant respectfully requests that notice of such requirement be directed to Applicant's below-signed representative. Applicant acknowledges the requirement to submit copies of foreign patent documents and non-patent literature in accordance with 37 C.F.R. 1.98(a)(2).

The Examiner is invited to contact the Applicants' Representative at the below-listed telephone number if there are any questions regarding this communication.


Respectfully submitted,

SERGEY A. VELICHKO ET AL.

By their Representatives,

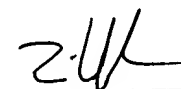
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Date Feb 8 '05

By   
John M. Dahl  
Reg. No. 44,639

**CERTIFICATE UNDER 37 CFR 1.8:** The undersigned hereby certifies that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to: MS Amendment, Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this 6 day of February, 2005.

Tina Kohav  
Name

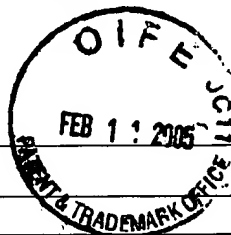
  
Signature

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Substitute for form 1449A/PTO

**INFORMATION DISCLOSURE  
STATEMENT BY APPLICANT**

(Use as many sheets as necessary)



Complete if Known

Application Number 09/834,751

Filing Date April 13, 2001

First Named Inventor Velichko, Sergey

Group Art Unit 2857

Examiner Name Miller, Craig

Sheet 1 of 1

Attorney Docket No: 303.750US1

**US PATENT DOCUMENTS**

Examiner Initial *	USP Document Number	Publication Date	Name of Patentee or Applicant of cited Document	Filing Date If Appropriate
	US-2002/0121915 A1	09/05/2002	Alonso Montull, J. I., et al.	03/05/2001
	US-2003/0200513 A1	10/23/2003	Bergman Reuter, B. L., et al.	04/23/2002
	US-2003/0212469 A1	11/13/2003	Wang, S , et al.	03/17/2003
	US-2004/0153979 A1	08/05/2004	Chang, F.	01/30/2003
	US-2004/0210413 A1	10/21/2004	Dorough, M. J., et al.	04/17/2003
	US-5,059,899	10/22/1991	Farnworth, W. D., et al.	08/16/1990
	US-6,785,413	08/31/2004	Barcomb, K. J., et al.	08/24/1999

**EXAMINER****DATE CONSIDERED**

Substitute Disclosure Statement Form (PTO-1449)

\* EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 809. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant. 1 Applicant's unique citation designation number (optional) 2 Applicant is to place a check mark here if English language Translation is attached

S/N 09/834,751

PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant: Sergey A. Velichko et al.

Examiner: Craig S. Miller

Serial No.: 09/834,751

Group Art Unit: 2857

Filed: April 13, 2001

Docket: 303.750US1

Title: CONCURRENT CONTROL OF SEMICONDUCTOR PARAMETRIC  
TESTING



COMMUNICATION CONCERNING RELATED APPLICATION(S)

Commissioner for Patents  
P.O. Box 1450  
Alexandria, VA 22313-1450

Applicants would like to bring to the Examiner's attention the following related application(s) in the above-identified patent application:

<u>Serial/Patent No.</u>	<u>Filing Date</u>	<u>Attorney Docket</u>	<u>Title</u>
10/924695	August 24, 2004	303.821US2	DYNAMICALLY ADAPTABLE SEMICONDUCTOR PARAMETRIC TESTING

Respectfully submitted,

SERGEY A. VELICHKO ET AL.

By Applicants' Representatives,

SCHWEGMAN, LUNDBERG, WOESSNER & KLUTH, P.A.  
P.O. Box 2938  
Minneapolis, MN 55402  
(612) 349-9581

Date Feb 8 '05

By [Signature]

John M. Dahl  
Reg. No. 44,639

CERTIFICATE UNDER 37 CFR 1.8: The undersigned hereby certifies that this correspondence is being deposited with the United States Postal Service with sufficient postage as first class mail, in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on this 8 day of February, 2005.

Tina Kohark  
Name

[Signature]  
Signature